


Symbol
Test Conditions
Characteristic Values
( $T_{J}=25^{\circ} \mathrm{C}$, unless otherwise specified)
min. typ. $^{\text {ty }}$ max.


IXSH 35N120B IXST 35N120B


TO-268 ( IXST)

$\mathrm{G}=$ Gate
C = Collector
$\mathrm{E}=$ Emitter

## Features

- Epitaxial Silicon drift region
- fast switching
- small tail current
- MOS gate turn-on for drive simplicity


## Applications

- AC motor speed control
- DC servo and robot drives
- Uninterruptible power supplies (UPS)
- Switched-mode and resonant-mode power supplies
- DC choppers IXST 35N120B

| Symbol | Test Conditions $\left(\mathrm{T}_{\mathrm{J}}=25^{\circ} \mathrm{C} \text {, unless } \mathrm{c}\right.$ | Characteristic Values ( $\mathrm{T}_{\mathrm{J}}=25^{\circ} \mathrm{C}$, unless otherwise specified) min. ${ }^{\text {typ. }}$ \| max. |  |
| :---: | :---: | :---: | :---: |
| $\mathrm{g}_{\text {ts }}$ | $I_{C}=I_{C 90} ; V_{C E}=10 \mathrm{~V},$ | 23 | S |
| $\begin{aligned} & \mathrm{C}_{\text {ies }} \\ & \mathrm{C}_{\text {oes }} \\ & \mathrm{C}_{\text {res }} \end{aligned}$ | $\mathrm{V}_{\mathrm{CE}}=25 \mathrm{~V}, \mathrm{~V}_{\mathrm{GE}}=0 \mathrm{~V}, \mathrm{f}=1 \mathrm{MHz}$ | $\begin{array}{r} 3600 \\ 260 \\ 75 \\ \hline \end{array}$ | pF <br> pF <br> pF |
| $\begin{aligned} & \mathbf{Q}_{\mathrm{g}} \\ & \mathbf{Q}_{\mathrm{ge}} \\ & \mathbf{Q}_{\mathrm{gc}} \end{aligned}$ | $\mathrm{I}_{\mathrm{C}}=\mathrm{I}_{\text {c90 }}, \mathrm{V}_{\mathrm{GE}}=15 \mathrm{~V}, \mathrm{~V}_{\text {CE }}=0.5 \mathrm{~V}_{\text {CES }}$ | $\begin{array}{r} 120 \\ 33 \\ 49 \end{array}$ | nC nc nC |
| $\begin{aligned} & t_{\mathrm{dol(0)}} \\ & t_{\text {ri }} \\ & t_{\mathrm{d}(\mathrm{lof})} \\ & t_{\mathrm{ti}} \\ & \mathrm{E}_{\mathrm{off}} \end{aligned}$ | Inductive load, $\mathrm{T}_{\mathrm{J}}=\mathbf{2 5}{ }^{\circ} \mathrm{C}$ $\begin{aligned} & \mathrm{I}_{\mathrm{C}}=\mathrm{I}_{\mathrm{C90}}, \mathrm{~V}_{\mathrm{GE}}=15 \mathrm{~V} \\ & \mathrm{R}_{G}=5 \Omega \\ & \mathrm{~V}_{\mathrm{CE}}=0.8 \mathrm{~V}_{\mathrm{CES}} \\ & \mathrm{Nato} \end{aligned}$ $\text { Note } 3$ | $\begin{array}{r} 36 \\ 27 \\ 160 \\ 180 \\ 5 \end{array}$ | $\begin{array}{rl}  & \mathrm{ns} \\ & \mathrm{~ns} \\ 300 & \mathrm{~ns} \\ 300 & \mathrm{~ns} \\ 9 & \mathrm{~mJ} \end{array}$ |
|  | Inductive load, $\mathrm{T}_{\mathrm{J}}=125^{\circ} \mathrm{C}$ $\begin{aligned} & \mathrm{I}_{\mathrm{C}}=\mathrm{I}_{\text {c90 }}, \mathrm{V}_{G E}=15 \mathrm{~V} \\ & \mathrm{R}_{\mathrm{G}}=5 \Omega, \mathrm{~V}_{\mathrm{CE}}=0.8 \mathrm{~V}_{\mathrm{CES}} \end{aligned}$ <br> Note 3 | $\begin{array}{r} 38 \\ 29 \\ 2.5 \\ 240 \\ 340 \\ 9 \end{array}$ | ns ns mJ ns ns mJ |
| $\begin{aligned} & \mathbf{R}_{\mathrm{tusc}} \\ & \mathbf{R}_{\mathrm{thck}} \end{aligned}$ | (TO-247) | 0.25 | $\begin{array}{r} 0.42 \mathrm{KW} \\ \mathrm{KW} \end{array}$ |

Notes:1. Device must be heatsunk for high temperature leakage current measurements to avoid thermal runaway.
2. Pulse test, $\mathrm{t} \leq 300 \mu \mathrm{~s}$, duty cycle $\leq 2 \%$
3. Switching times may increase for $\mathrm{V}_{\mathrm{CE}}$ (Clamp) $>0.8 \mathrm{~V}_{\text {CES }}$, higher $\mathrm{T}_{\mathrm{J}}$ or increased $R_{G}$.

## TO-247 AD Outline (IXSH)



TO-268 Outline (IXST)


| Dim. | Millimeter |  | Inches |  |
| :---: | :---: | :---: | :---: | :---: |
|  | Min. | Max. | Min. | Max. |
| A | 4.9 | 5.1 | . 193 | . 201 |
| $\mathrm{A}_{1}$ | 2.7 | 2.9 | . 106 | . 114 |
| $\mathrm{A}_{2}$ | . 02 | . 25 | . 001 | . 010 |
| b | 1.15 | 1.45 | . 045 | . 057 |
| $\mathrm{b}_{2}$ | 1.9 | 2.1 | . 75 | . 83 |
| C | . 4 | . 65 | . 016 | . 026 |
| D | 13.80 | 14.00 | . 543 | . 551 |
| E | 15.85 | 16.05 | . 624 | . 632 |
| $\mathrm{E}_{1}$ | 13.3 | 13.6 | . 524 | . 535 |
| e |  | BSC |  | BSC |
| H | 18.70 | 19.10 | . 736 | . 752 |
| L | 2.40 | 2.70 | . 094 | . 106 |
| L1 | 1.20 | 1.40 | . 047 | . 055 |
| L2 | 1.00 | 1.15 | . 039 | . 045 |
| L3 |  | BSC | . 0 | BSC |
| L4 | 3.80 | 4.10 | . 150 | . 161 |

